54ACT11833, 74ACT11833 8-BIT TO 9-BIT PARITY BUS TRANSCEIVERS

D3449, MARCH 1990-REVISED OCTOBER 1990

- Inputs are TTL-Voltage Compatible
- High-Speed Bus Transcelvers With Parity Generator/Checker
- Parity-Error-Flag Open-Drain Output
- Register for Storage of the Parity-Error Flag
- Flow-Through Architecture Optimizes PCB Layout
- Center-Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise
- EPIC™ (Enhanced-Performance Implanted CMOS) 1-µm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs

description

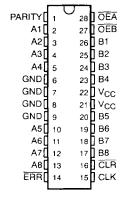
The 'ACT11833 is an 8-bit to 9-bit parity transceiver designed for two-way communication between data buses. When data is transmitted from the A bus to the B bus, a parity bit is generated. When data is transmitted from the B bus to the A bus with its corresponding parity bit, the ERR output will indicate whether or not an error in the B data has occurred. The output enable inputs OEA and OEB can be used to disable the device so that the buses are effectively isolated.

A 9-bit parity generator/checker generates a parity-odd output (PARITY) and monitors the parity of the I/O ports with an open-drain parity

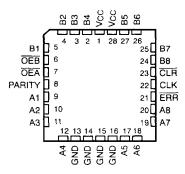
error flag ($\overline{\text{ERR}}$). $\overline{\text{ERR}}$ is clocked into the register on the rising edge of the CLK input. The error flag register is cleared with a low pulse on the $\overline{\text{CLR}}$ input. When both $\overline{\text{OEA}}$ and $\overline{\text{OEB}}$ are low, data is transferred from the A bus to the B bus and inverted parity is generated. Inverted parity is a forced error condition that gives the designer more system diagnostic capability.

The 54ACT11833 is characterized for operation over the full military temperature range of -55° C to 125°C. The 74ACT11833 is characterized for operation from -40° C to 85°C.

54ACT11833 . . . JT PACKAGE 74ACT11833 . . . DW OR NT PACKAGE (TOP VIEW)



54ACT11833 . . . FK PACKAGE (TOP VIEW)



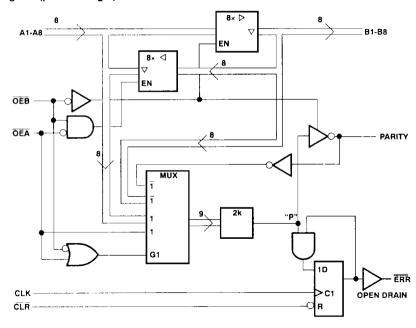
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Function Table

			INPUT	S			OUTF	UT AND I/O)	
ÖEB	OEA	CLR	CLK	Al Σ of H's	Bi [†] Σ of H's	А	В	PARITY	ERR	FUNCTION
L	Н	х	Х	Odd Even	NA	NA	Α	L H	NΑ	A data to B bus and Generate Parity
н	L	Н	•	NA	Odd Even	В	NA	NA	rΙ	B Data to A Bus and Check Parity
X	Х	L	X	Х	X	Х	NA	NA .	Η	Clear Error Flag Register
н	н	н Н Н	No† No†	X X Odd Even	×	z	z	Z	rIIS	Isolation [‡]
L	L	х	Х	Odd Even	NA	NA	Α	H L	NA	A Data to B Bus and Generate Inverted Parity

logic diagram (positive logic)





NA ¬ Not applicable, NC = No change, X = Don't care

† Summation of high-level inputs includes PARITY along with Bi inputs.

‡ In this mode, the ÉŘŘ output, when clocked, shows inverted parity of the A bus.

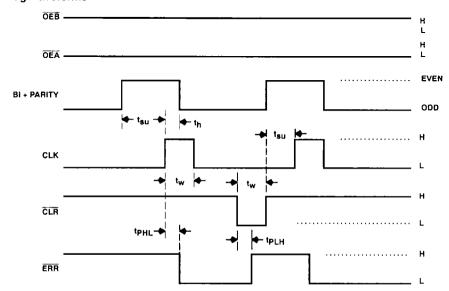
D3449, MARCH 1990-REVISED OCTOBER 1990

Error-Flag Function Table

INP	uts	INTERNAL TO DEVICE	OUTPUT PRE-STATE	ОИТРИТ	FUNCTION
CLR	CLK	POINT "P"	ERR n-1	ERR	į.
Н	†	Н	н	н	
Н	†	x	L	L	Sample
н	†	L	×	L	
L	X	x	×	Н	Clear

ERR n-1 represents the state of the ERR output before any changes at CLR, CLK, or point "P".

error-flag waveforms



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D3449, MARCH 1990- REVISED OCTOBER 1990

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V _{CC}	7 V
Input voltage range, V ₁ (see Note 1)	
input voltage range, v1 (see Note 1)	.5 V
Output voltage range, V_0 (see Note 1)	.5 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC})	mA
Continuous output current, I _O (V _O = 0 to V _{CC})	mΑ
Continuous current through V _{CC} or GND pins±225	mΑ
Storage temperature range 65°C to 15	O°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		54	54ACT11833			74ACT11833		
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	4.5	5	5.5	٧
VIН	High-level input voltage	2			2			V
VIL	Low-level input voltage			0.8			0.8	V
VΙ	Input voltage	0		Vcc	0		Vcc	V
٧o	Output voitage	0		Vcc	0		Vcc	V
юн	High-level output current			- 24			- 24	mA
OL	Low-level output current			24			24	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	0		10	0		10	ns/V
TA	Operating free-air temperature	- 55		125	- 40		85	°C



NOTE 1: The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	DADAMETED	DAMETED TEST CONDITIONS		T	A = 25°C	;	54ACT	11833	74ACT11833			
	PARAMETER	TEST CONDITIONS	vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
			4.5 V	4.4			4.4		4.4			
		I _{OH} = - 50 μA	5.5 V	5.4			5.4		5.4			
\/ -	All outputs except		4.5 V	3.94			3.7		3.8			
∨он	ERR	I _{OH} = 24 mA	5.5 V	4.94			4.7		4.8		٧	
	i	I _{OH} = 50 mA [†]	5.5 V				3.85					
		IOH = - 75 mA [†]	5.5 V						3.85			
			4.5 V			0.1		0.1		0.1		
		I _{OL} = 50 μA	5.5 V			0.1		0.1		0.1		
1/			4.5 V			0.36		0.5		0.44		
VoL		I _{OL} = 24 mA	5.5 V			0.36		0.5		0.44	٧	
		IOL = 50 mA [†]	5.5 V					1.65				
		I _{OL} = 75 mA [†]	5.5 V							1.65		
lj -	OEA, OEB, CLK, and CLR	V _I = V _{CC} or GND	5.5 V			± 0.1		± 1		± 1	μΑ	
loz	A or B ports, PARITY‡	VO = VCC or GND	5.5 V			± 0.5		± 10		± 5	μΑ	
lcc		V _I = V _{CC} or GND, I _O = 0	5.5 V			8		160		80	μΑ	
ΔICC§		One input at 3.4 V, Other inputs at GND or VCC	5.5 V			0.9		1		1	mA	
Ci	OEA, OEB, CLK, and CLR	VI = VCC or GND	5 V	·	4.5						_	
Cio	A or B ports, PARITY	VO = VCC or GND	5 V		12						рF	

t Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

timing requirements over recommended operating free-air temperature range, V_{CC} = 5 V $_{\pm}$ 0.5 V (unless otherwise noted) (see Note 2)

			TA = 25°C		54ACT11833		74ACT11833			
			MIN	MAX	MIN	MAX	MIN	MAX	UNIT	
tw		CLK high	5		5		5		ns	
	Pulse duration	CLK low	5		5		5			
		CLR low	5		5		5			
		Bi and PARITY	14		14		14		nş	
lsu	Setup time before CLK†	CLR inactive	2		2		2			
th	Hold time after CLK †, Bi and	PARITY	0		0		0		ns	

NOTE 2: Load circuit and voltage waveforms are shown in Section 1.

operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25 ^{\circ}\text{C}$

	PARAMETER	TEST CO	TYP	UNIT			
			A to B			87	
C _{pd}	Power dissipation apposits not not transcribe.	Outputs enabled	B to A	C _L = 50 pF,	f = 1 MHz	60	ρF
	Power dissipation capacitance per transceiver	L Outputs disabled E	A to B	C _L = 50 pF,	f = 1 MHz	28	
			B to A			8	pF



[‡] For I/O ports, the parameter IOZ includes the input leakage current.

[§] This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V to VCC.